

Search Notes

Application/Control No.

10/630,789

Examiner

Syed Zaidi

Applicant(s)/Patent under
Reexamination

CHEN ET AL.

Art Unit

2616

SEARCHED

Class	Subclass	Date	Examiner
370	241	2/14/2008	SZ

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
AST image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO, and IBM_TDB (please see search history)	2/14/2008	SZ
Inventor : CHEN ET AL.	2/14/2008	SZ
EEE Xplore Database(http://ieeexplore.ieee.org/Xplore/DynWel.jsp)	2/14/2008	SZ
(370/248 370/241 370/241.1 370/242 370/243 370/244 370/245 370/246 370/247 370/248 370/249 370/250).ccis.	2/14/2008	SZ
Consulted with SPE Seema S. Rao	2/14/2008	SZ